

## **Fabrication of silicon-integrated telecom-wavelength photonic-crystal surface-emitting lasers using micro-transfer printing**

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Photonic-crystal surface-emitting lasers (PCSELS) are attracting significant interest for a range of different applications in materials processing, communication and sensing [1]. As a key attribute, they can produce large-area singlemode emission power using a two-dimensional photonic crystal cavity where in-plane propagating waves are diffracted in the vertical direction. While superior PCSEL performance so far has been achieved using GaAs-based devices with emission in the near-infrared wavelength regime, there is an increasing interest in longer-wavelength InP-based PCSELS for a range of applications, e.g. in fiber-optical telecommunication. This typically requires significantly higher modulation rates than what is available from standard PCSEL designs aiming for large-area devices with high emission power. Smaller-area devices are limited by lateral loss, which can be mitigated using a more advanced grating layer that provide in-plane feedback [2]. However, such grating layers need to include differently sized features which is challenging to realize using epitaxial regrowth, the present standard fabrication method for high-performance PCSELS. Here we report on the development of 1.55- $\mu\text{m}$  hybrid InP/Si PCSELS [3] using an industrial micro-transfer print (MTP) process. In this approach, an InP-based active layer is superimposed upon a pre-patterned silicon substrate. This MTP-based technique enables an arbitrary grating layer geometry, while requiring optimization of the InP-based membrane pre-processing for high-quality layer integrity and interface control.

1. S. Noda et al., IEEE J. Sel. Top. Quantum Electronics, 2017
2. T. Inoue et al., Opt. Express, 2020
3. C. Reuterskiöld Hedlund et al., Physica Status Solidi, 2020